

**Search Notes**

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Examiner

Nam Huynh

Applicant(s)/Patent under  
Reexamination

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Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
379	142.01- 142.09	11/27/2006	NTH
709	1-6	11/27/2006	NTH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	11/27/2006	NTH